

Geotechnical investigation and testing — Sampling methods and groundwater measurements —

**Part 2: Qualification criteria for
enterprises and personnel**

ICS 93.020

National foreword

This Draft for Development was published by BSI. It is the UK implementation of CEN ISO/TS 22475-2:2006.

This publication is not to be regarded as a British Standard.

It is being issued in the Draft for Development series of publications and is of a provisional nature. It should be applied on this provisional basis, so that information and experience of its practical application can be obtained.

Comments arising from the use of this Draft for Development are requested so that UK experience can be reported to the European organization responsible for its conversion to a European standard. A review of this publication will be initiated not later than 3 years after its publication by the European organization so that a decision can be taken on its status. Notification of the start of the review period will be made in an announcement in the appropriate issue of *Update Standards*.

According to the replies received by the end of the review period, the responsible BSI Committee will decide whether to support the conversion into a European Standard, to extend the life of the Technical Specification or to withdraw it. Comments should be sent to the Secretary of the responsible BSI Technical Committee at British Standards House, 389 Chiswick High Road, London W4 4AL.

The UK participation in its preparation was entrusted by Technical Committee B/526, Geotechnics, to Subcommittee B/526/3, Site investigation and ground testing.

A list of organizations represented on this committee can be obtained on request to its secretary.

This publication does not purport to include all the necessary provisions of a contract. Users are responsible for its correct application.

This Draft for Development was published under the authority of the Standards Policy and Strategy Committee on 31 July 2007

© BSI 2007

ISBN 978 0 580 52921 4

Amendments issued since publication

Amd. No.	Date	Comments